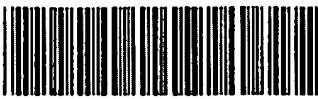


<b>Issue Classification</b>		<b>Application/Control No.</b>		<b>Applicant(s)/Patent under Reexamination</b>	
		10/644,867		ASADA, TOSHIAKI	
Examiner		Art Unit			
Kyle M. Riddle		3748			

## ISSUE CLASSIFICATION

ORIGINAL			CROSS-REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
123	90.15	123	568.14	677	679	687	316	568.11
INTERNATIONAL CLASSIFICATION			60	285				
F	0	1	L	1/34				
				1				
				1				
				1				
				1				
<i>Spur M. Riddle 10/31/05</i>			THOMAS DENION SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700				Total Claims Allowed: 22	
Kyle M. Riddle (Assistant Examiner) (Date)			Thomas Denion (Primary Examiner) (Date)				O.G. Print Claim(s)	O.G. Print Fig.
<i>Dawn Poulter 10/31/05</i> (Legal Instruments Examiner) (Date)			Thomas Denion (Date)				1	1,3a,3

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.O.		<input type="checkbox"/> R. 1.47	
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7	5	35	65	95	125	155	185
8	6	36	66	96	126	156	186
9	7	37	67	97	127	157	187
10	8	38	68	98	128	158	188
12	9	39	69	99	129	159	189
13	10	40	70	100	130	160	190
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19	16	46	76	106	136	166	196
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27	57	87	117	147	147	177	207
28	58	88	118	148	148	178	208
29	59	89	119	149	149	179	209
30	60	90	120	150	180		210